11/21/03

Form PTO-1449 (Rev.7-80)	U.S. Department of Commerce Patent & Trademark Office	ATTY.DOCKET NO. 9-14774-1US-1-1	SERIAL NO. 10/717460 Not yet assigned.
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT DAVID F. SKOLL et al.	
		FILING DATE: Concurrently herewith. 11-21-03	GROUP 2825

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Examiner PAUL DINH	Date considered 4/25/05

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.